

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/720,540	HAYASHI ET AL.
	Examiner David Buttner	Art Unit 1712

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
524	all	8/4/2006	DB
525	all	8/4/2006	DB
473	all	8/4/2006	DB